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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: R. Nagamine et al.

Serial No.: 10/026,532

Group Art Unit: 2133

Filed: December 27, 2001

Examiner: Cynthia H. Britt

For: TEST CIRCUIT FOR LOGICAL INTEGRATED CIRCUIT AND METHOD FOR  
TESTING SAME

Honorable Commissioner of Patents  
Alexandria, VA 22313-1450

**RECORD OF TELEPHONE INTERVIEW  
AND AMENDMENT UNDER 37 C.F.R. §1.111**

Sir:

In response to the Office Action dated September 28, 2005, please amend the above-  
identified application as follows: